

**Summary of Supporting Information:**

**JCET 8L SOIC AD8051/AD8091 (XFCB):**

Test Name	Specification	Conditions	Device	Package	Lot #	Sample Size	Qty. Failures
Autoclave (AC) <sup>1</sup>	JESD22-A102	121°C 100%RH 2atm 96 hours	AD8091	JCET 8-SOIC_N	Q7515.2	77	0
					Q7515.16	77	0
					Q7515.33	77	0
Biased HAST (HAST) <sup>2</sup>	JESD22-A110	130°C 85%RH 2atm, Biased 96 hours	AD8091	JCET 8-SOIC_N	Q7515.17	77	0
					Q7515.19	77	0
					Q7515.36	77	0
High Temperature Storage Life (HTSL)	JESD22-A103	150°C 1,000 hours	AD8091	JCET 8-SOIC_N	Q7515.26	77	0
Solder Heat Resistance (SHR) <sup>1</sup>	ADI-0049		AD8091	JCET 8-SOIC_N	Q7515.24	16	0
					Q7515.25	16	0
					Q7515.42	16	0
Temperature Cycling (TC) <sup>1</sup>	JESD22-A104	-65°C / +150°C 500 cycles	AD8091	JCET 8-SOIC_N	Q7515.8	77	0
					Q7515.21	77	0
					Q7515.22	77	0

**JCET 8L MSOP AD8131(XFCB)**

Test Name	Specification	Conditions	Device	Package	Lot #	Sample Size	Qty. Failures
Autoclave (AC) <sup>1</sup>	JESD22-A102	121°C 100%RH 2atm 96 hours	AD8131	JCET 8-MINI_SO	Q7621.1	77	0
					Q7621.2	77	0
					Q7621.3	77	0
Biased HAST (HAST) <sup>1</sup>	JESD22-A110	130°C 85%RH 2atm, Biased 96 hours	AD8131	JCET 8-MINI_SO	Q7621.8	77	0
					Q7621.9	77	0
					Q7621.10	77	0
High Temperature Storage Life (HTSL)	JESD22-A103	150°C 1,000 hours	AD8131	JCET 8-MINI_SO	Q7621.22	77	0
Solder Heat Resistance (SHR) <sup>1</sup>	ADI-0049	See Below	AD8131	JCET 8-MINI_SO	Q7621.25	21	0
					Q7621.26	21	0
					Q7621.27	21	0
Temperature Cycling (TC) <sup>1</sup>	JESD22-A104	-65°C / +150°C 500 cycles	AD8131	JCET 8-MINI_SO	Q7621.15	77	0
					Q7621.16	77	0
					Q7621.17	77	0

JCET 8L SOIC OP282 (Large Die)

Test Name	Specification	Conditions	Package	Device	Lot #	Sample Size	Qty. Failures
Autoclave (AC) <sup>1</sup>	JESD22-A102	121°C 100%RH 2atm 96 hours	JCET 8-SOIC_N	OP282	Q7835.100	77	0
					Q7835.101	77	0
					Q7835.102	77	0
Biased HAST (HAST) <sup>1</sup>	JESD22-A110	130°C 85%RH 2atm, Biased 96 hours	JCET 8-SOIC_N	OP282	Q7835.200	77	0
					Q7835.201	77	0
					Q7835.202	77	0
High Temperature Storage Life (HTSL)	JESD22-A103	150°C 1,000 hours	JCET 8-SOIC_N	OP282	Q7835.300	77	0
Solder Heat Resistance (SHR) <sup>1</sup>	ADI-0049		JCET 8-SOIC_N	OP282	Q7835.400	21	0
					Q7835.401	21	0
					Q7835.402	21	0
Temperature Cycling (TC) <sup>1</sup>	JESD22-A104	-65°C / +150°C 500 cycles	JCET 8-SOIC_N	OP282	Q7835.500	77	0
					Q7835.501	77	0
					Q7835.502	77	0

JCET 8L MSOP OP777 (Large Die)

Test Name	Specification	Conditions	Package	Device	Lot #	Sample Size	Qty. Failures
Autoclave (AC) <sup>1</sup>	JESD22-A102	121°C 100%RH 2atm 96 hours	JCET 8-MINI_SO	OP777	Q7795.100	77	0
					Q7795.101	77	0
					Q7795.102	77	0
Biased HAST (HAST) <sup>1</sup>	JESD22-A110	130°C 85%RH 2atm, Biased 96 hours	JCET 8-MINI_SO	OP777	Q7795.200	77	0
					Q7795.201	77	0
					Q7795.202	77	0
High Temperature Storage Life (HTSL)	JESD22-A103	150°C 1,000 hours	JCET 8-MINI_SO	OP777	Q7795.300	77	0
Solder Heat Resistance (SHR) <sup>1</sup>	ADI-0049		JCET 8-MINI_SO	OP777	Q7795.400	16	0
					Q7795.401	16	0
					Q7795.402	16	0
Temperature Cycling (TC) <sup>1</sup>	JESD22-A104	-65°C / +150°C 500 cycles	JCET 8-MINI_SO	OP777	Q7795.500	77	0
					Q7795.501	77	0
					Q7795.502	77	0

JCET 16L TSSOP ADM3202 (Large Die):

Test Name	Specification	Conditions	Package	Device	Lot #	Sample Size	Qty. Failures
Autoclave (AC) <sup>1</sup>	JESD22-A102	121°C 100%RH 2atm 96 hours	JCET 16- TSSOP_4.4	ADM3202	Q7696.103	77	0
					Q7696.104	77	0
					Q7696.105	77	0
Biased HAST (HAST) <sup>1</sup>	JESD22-A110	130°C 85%RH 2atm, Biased 96 hours	JCET 16- TSSOP_4.4	ADM3202	Q7696.203	77	0
					Q7696.204	77	0
					Q7696.205	77	0
High Temperature Storage Life (HTSL)	JESD22-A103	150°C 1,000 hours	JCET 16- TSSOP_4.4	ADM3202	Q7696.301	77	0
Solder Heat Resistance (SHR) <sup>1</sup>	ADI-0049		JCET 16- TSSOP_4.4	ADM3202	Q7696.403	21	0
					Q7696.404	21	0
					Q7696.405	21	0
Temperature Cycling (TC) <sup>1</sup>	JESD22-A104	-65°C / +150°C 500 cycles	JCET 16- TSSOP_4.4	ADM3202	Q7696.503	77	0
					Q7696.504	77	0
					Q7696.505	77	0

ASE 8L SOIC AD8051/AD8091 (XFCB):

Test Name	Specification	Conditions	Device	Package	Lot #	Sample Size	Qty. Failures
Autoclave (AC) <sup>1</sup>	JESD22-A102	121°C 100%RH 2atm 96 hours	AD8091	ASE- Shanghai 8- SOIC_N	Q7512.100	77	0
					Q7512.101	77	0
					Q7512.102	77	0
Biased HAST (HAST) <sup>2</sup>	JESD22-A110	130°C 85%RH 2atm, Biased 96 hours	AD8091	ASE- Shanghai 8- SOIC_N	Q7512.200	77	0
					Q7512.201	77	0
					Q7512.202	77	0
High Temperature Storage Life (HTSL)	JESD22-A103	150°C 1,000 hours	AD8091	ASE- Shanghai 8- SOIC_N	Q7512.300	77	0
Solder Heat Resistance (SHR) <sup>1</sup>	ADI-0049		AD8091	ASE- Shanghai 8- SOIC_N	Q7512.400	15	0
					Q7512.401	15	0
					Q7512.402	15	0
Temperature Cycling (TC) <sup>1</sup>	JESD22-A104	-65°C / +150°C 500 cycles	AD8091	ASE- Shanghai 8- SOIC_N	Q7512.500	77	0
					Q7512.501	77	0
					Q7512.502	77	0

ASE 8L PDIP OP270:

Test Name	Specification	Conditions	Device	Package	Lot #	Sample Size	Qty. Failures
Autoclave (AC)	JESD22-A102	121°C 100%RH 2atm 96 hours	OP270	ASE- Shanghai 8-PDIP	Q7534.100	77	0
					Q7534.101	77	0
					Q7534.102	77	0
Biased HAST (HAST)	JESD22-A110	130°C 85%RH 2atm, PWR CYC 96 hours	OP270	ASE- Shanghai 8-PDIP	Q7534.200	77	0
					Q7534.201	77	0
					Q7534.202	77	0
High Temperature Storage Life (HTSL)	JESD22-A103	150°C 1,000 hours	OP270	ASE- Shanghai 8-PDIP	Q7534.300	77	0
					Q7534.301	77	0
					Q7534.302	77	0
Temperature Cycling (TC)	JESD22-A104	-65°C / +150°C 500 cycles	OP270	ASE- Shanghai 8-PDIP	Q7534.400	77	0
					Q7534.401	77	0
					Q7534.402	77	0